



CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

Astute Electronics Limited
Rutherford Close, Stevenage
Hertfordshire, SG1 2EF, United Kingdom
(and satellite location as shown on the scope)

Fulfills the requirements of

ISO/IEC 17025:2017

and

AS6171 Detection of Suspect/Counterfeit Parts Accreditation Program

In the field of

TESTING

This certificate is valid only when accompanied by a current scope of accreditation document.
The current scope of accreditation can be verified at www.anab.org.

Jason Stine, Vice President

Expiry Date: 22 November 2026

Certificate Number: AT-3329



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

Astute Electronics Limited

Rutherford Close, Stevenage, Hertfordshire, SG1 2EF, United Kingdom

Tony Hall tony.hall@astutegroup.com

+44 (0) 1438 909835

TESTING

ISO/IEC 17025 Accreditation Granted: **22 November 2024**

Certificate Number: **AT-3329**

Certificate Expiry Date: **22 November 2026**

In recognition of a successful assessment to ISO/IEC 17025:2017 General Requirements for the competence of Testing and Calibration Laboratories, AS6171 General Requirements, and the requirements of the ANAB SR 2429 – Labs Performing Detection of Suspect/Counterfeit Parts Under AS6171 program, accreditation is granted to the **Astute Electronics Limited** to perform the following AS6171 slash sheet tests:

Non-Destructive Testing

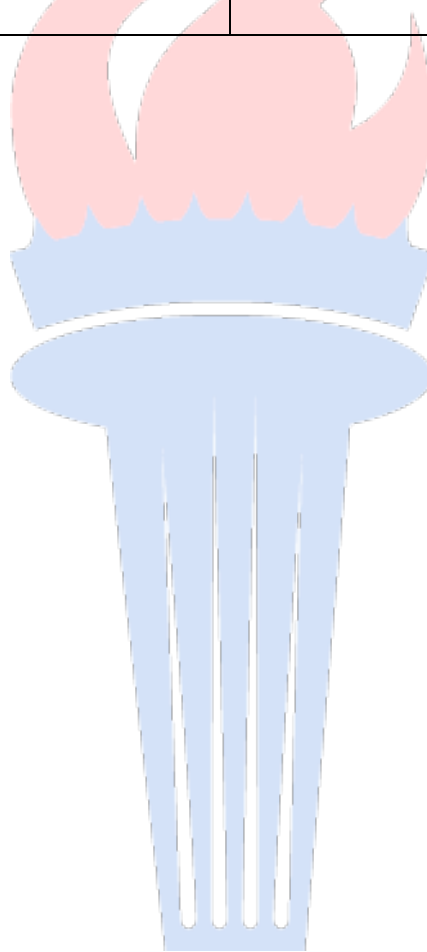
Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
External Visual Inspection (EVI)	AS6171/2 (Methods A & B)	Electrical, Electronic and Electromechanical (EEE) Components	Digital Camera Microscopes Scale
Dimensional Inspection	AS6171/2 (Method E)		Keyence LM-1100
Radiographic (X-Ray) Inspection	AS6171/5		Glenbrook Jewelbox 70T/90T
X-Ray Fluorescence (XRF) Inspection	AS6171/3		Fischer XDAL Spectrometer XRF System
Scanning Electron Microscope (SEM)	AS6171/2 (Method F)		Hitachi TM4000

Mechanical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Resistance to Solvents (Remarking and Resurfacing)	AS6171/2 (Methods C & D)	Electrical, Electronic and Electromechanical (EEE) Components	Chemicals Scrape Knife

Mechanical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Solderability Test	J-STD-002	Electrical, Electronic and Electromechanical (EEE) Components	Gen3 Must 3 Solderability Test System
Heated Solvent Tests	AS6171/2 (Method D)	Electrical, Electronic and Electromechanical (EEE) Components	Hot Plate Digital Thermometer Multiple Chemicals
Delid/Decapsulation Physical Analysis (DDPA)	AS6171/4	Electrical, Electronic and Electromechanical (EEE) Components	Tabletop Furnace Hot Plate Chemicals Digital Camera Microscopes VHX-7000



SATELLITE SITE

Astute GMBH

Pfarrer-Huber-Ring 8, Feldkirchen-Westerham 83620, Germany

Tony Hall tony.hall@astutegroup.com

+44 7918 627921

TESTING

Non-Destructive Testing

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
External Visual Inspection (EVI)	AS6171/2 (Methods A & B)	Electrical, Electronic and Electromechanical (EEE) Components	Dino-Lite Microscope Camera Scale
Dimensional Inspection	AS6171/2 (Method E)		Keyence LM-1100 Vernier Calipers
Radiographic (X-Ray) Inspection	AS6171/5		Glenbrook Jewelbox 90T
X-Ray Fluorescence (XRF) Inspection	AS6171/3		Fischer XDAL 237SDD Spectrometer
Scanning Electron Microscope (SEM)	AS6171/2 (Method F)		Hitachi TM4000+ SEM Oxford Instruments Xplore Compact 30

Mechanical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Resistance to Solvents (Remarking and Resurfacing)	AS6171/2 (Methods C & D)	Electrical, Electronic and Electromechanical (EEE) Components	Chemicals Scrape Knife Hot Plate Digital Thermometer
Solderability Test	J-STD-002	Electrical, Electronic and Electromechanical (EEE) Components	Gen3 Must 3 Solderability Test System
Heated Solvent Tests	AS6171/2 (Method D)	Electrical, Electronic and Electromechanical (EEE) Components	Hot Plate Digital Thermometer Multiple Chemicals

Mechanical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Delid/Decapsulation Physical Analysis (DDPA)	AS6171/4	Electrical, Electronic and Electromechanical (EEE) Components	Thermofisher Muffle Oven Keyence Microscope VHX-7000



Jason Stine, Vice President

